Form PTO-1449   U.S. Department of Commerce   Atty. Docket No. 501.30598CC3
Equivalent   Patent and Trademark Office   Serial No. (not yet assigned)
                                                  Applicant: MORIOKA et al
                                                  Filing Date: March 14, 2001
                                                  Group:
                                                  Page 1 of 2

U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class	Subclass	Filing Date If Approp.
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𝒯𝓋	59-65428	4/84	Japan				
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*Examiner: Initial if reference considered, whether or not citation is in
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